

SIGC81T60NC

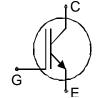
IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

• IGBT-Modules



Applications:

• drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code	
SIGC81T60NC	60NC 600V 100A 8.99 x 8.99 mm ²		sawn on foil	Q67041-A4694-		
SIGCOTTOUNG	0000	TOUA	0.33 x 0.33 11111	Sawii Oii ioii	A001	

MECHANICAL PARAMETER:

Raster size	8.99 x 8.99			
Area total / active	80.82 / 72.6			
Emitter pad size	8x(1.77x2.82)			
Gate pad size	0.78 x 1.51			
Thickness	100	μm		
Wafer size	150	mm		
Flat position	90	deg		
Max.possible chips per wafer	169			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm Al Si 1%			
Collector metallization	ion 1400 nm Ni Ag –system suitable for epoxy and soft solder die bondin			
Die bond	electrically conductive glue or solder			
Wire bond	Al, ≤500μm			
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



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MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _j =25 °C	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	300	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i arameter		Conditions	min.	typ.	max.	Jiii.
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =4mA	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =100A	1.7	2.1	2.5	V
Gate-emitter threshold voltage	V _{GE(th)}	I _C =1.5mA, V _{GE} =V _{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V			7	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V, V _{GE} =20V			300	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions		Value		Unit
raiailietei	Symbol	Conditions	min.	typ.	max.	Oilit
Input capacitance	Ciss	V _{CE} =25V	-	4300	-	pF
Output capacitance	Coss	V _{GE} =0V	-	tbd	-	
Reverse transfer capacitance	Crss	f=1MHz	-	400	-	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

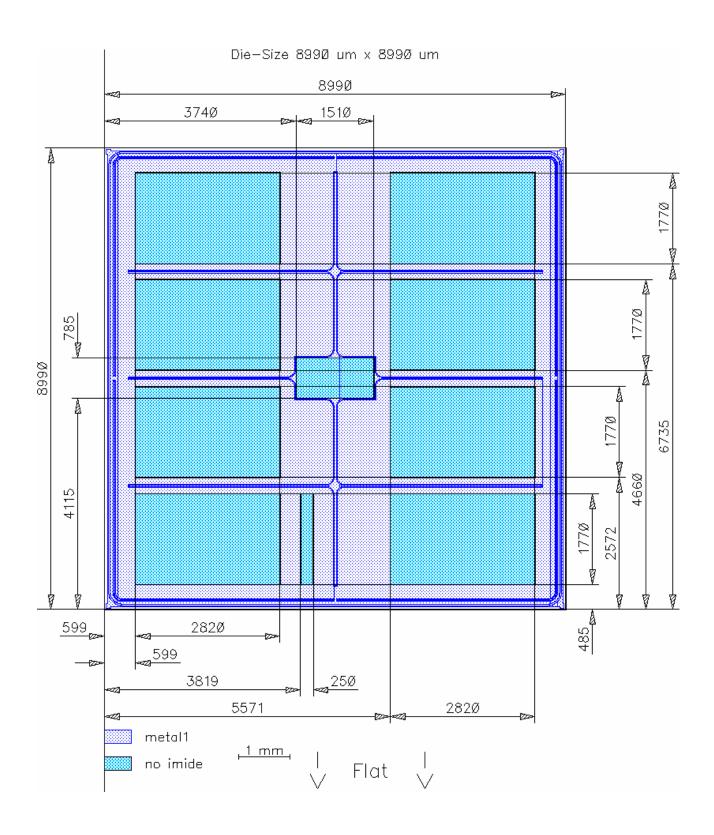
Parameter	Symbol	Conditions 1)	Value			Unit
	Symbol	Conditions	min.	typ.	max.	Onne
Turn-on delay time	$t_{d(on)}$	T_j =125°C V_{CC} =300V	-	95	-	ns
Rise time	t_{r}	I _C =100A	-	30	-	
Turn-off delay time	$t_{d(off)}$	$V_{\text{GE}} = \pm 15 \text{V}$ $R_{\text{G}} = 2.2 \Omega$	-	200	-	
Fall time	t_{f}	7.6-2.22	-	35	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.





CHIP DRAWING:





SIGC81T60NC

FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet	tbd
device data silect	

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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